SILICON POWER MOS FET NE5520379A

3.2 V OPERATION SILICON RF POWER LDMOS FET FOR GSM/DCS DUAL-BAND PHONE TRANSMISSION AMPLIFIERS

DESCRIPTION

NEC

The NE5520379A is an N-channel silicon power MOS FET specially designed as the transmission power amplifier for 3.2 V GSM 900 handsets. Dies are manufactured using our NEWMOS technology and housed in a surface mount package. This device can deliver 34.6 dBm output power with 68% power efficiency at 915 MHz under the 2.8 V supply voltage.

FEATURES

•	High output power	: Pout = 35.5 dBm TYP. (VDs = 3.2 V, VGs = 2.5 V, f = 915 MHz, Pin = 25 dBm)
		: $P_{out} = 33.0 \text{ dBm TYP}$. ($V_{DS} = 3.2 \text{ V}$, $V_{GS} = 2.5 \text{ V}$, $f = 1.785 \text{ MHz}$, $P_{in} = 25 \text{ dBm}$)
•	High power added efficiency	: η_{add} = 65% TYP. (VDs = 3.2 V, VGs = 2.5 V, f = 915 MHz, Pin = 25 dBm)
		: η_{add} = 35% TYP. (V _{DS} = 3.2 V, V _{GS} = 2.5 V, f = 1 785 MHz, P _{in} = 25 dBm)
•	High linear gain	: G_L = 16.0 dB TYP. (VDs = 3.2 V, VGs = 2.5 V, f = 915 MHz, Pin = 10 dBm)
		: $G_L = 8.5 \text{ dB TYP}$. (VDS = 3.2 V, VGS = 2.5 V, f = 1 785 MHz, Pin = 10 dBm)
•	Surface mount package	: 5.7 \times 5.7 \times 1.1 mm MAX.
•	Single supply	: VDS = 2.8 to 6.0 V

APPLICATIONS

*

- Digital cellular phones : 3.2 V GSM/DCS Dual-Band handsets
- Others : General purpose amplifiers for 1.6 to 2.0 GHz TDMA applications

ORDERING INFORMATION

Part Number	Package	Marking	Supplying Form
NE5520379A-T1	79A	A3	12 mm wide embossed tapingGate pin face the perforation side of the tapeQty 1 kpcs/reel
NE5520379A-T1A			12 mm wide embossed tapingGate pin face the perforation side of the tapeQty 5 kpcs/reel

Remark To order evaluation samples, contact your nearby sales office.

Part number for sample order: NE5520379A

Caution Observe precautions when handling because these devices are sensitive to electrostatic discharge.

The information in this document is subject to change without notice. Before using this document, please confirm that this is the latest version. Not all devices/types available in every country. Please check with local NEC Compound Semiconductor Devices representative for availability and additional information.

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ABSOLUTE MAXIMUM RATINGS (T_A = +25°C)

Parameter	Symbol	Ratings	Unit
Drain to Source Voltage	Vds	15.0	V
Gate to Source Voltage	Vgs	5.0	V
Drain Current	lo	1.5	А
Drain Current (Pulse Test)	D Note	3.0	А
Total Power Dissipation	Ptot	20	W
Channel Temperature	Tch	125	°C
Storage Temperature	Tstg	-65 to +125	°C

Note Duty Cycle \leq 50%, Ton \leq 1 s

RECOMMENDED OPERATING CONDITIONS

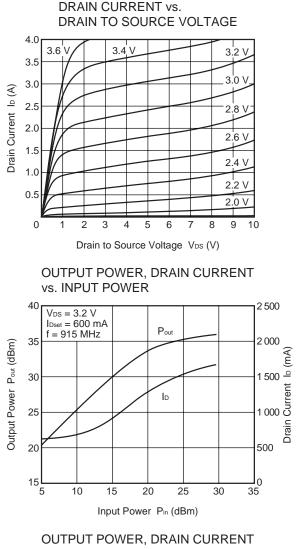
	Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit
*	Drain to Source Voltage	Vds		2.8	3.2	6.0	V
	Gate to Source Voltage	Vgs		0	2.5	3.5	V
	Drain Current (Pulse Test)	lo	Duty Cycle \leq 50%, T _{on} \leq 1 s	-	1.75	2.0	А
	Input Power	Pin	f = 1.8 GHz, V _{DS} = 3.6 V	24	25	26	dBm

ELECTRICAL CHARACTERISTICS (TA = +25°C)

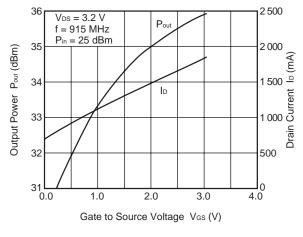
Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit
Gate to Source Leak Current	lgss	V _{GS} = 6.0 V	-	-	100	nA
Drain to Source Leakage Current (Zero Gate Voltage Drain Current)	ldss	V _{DS} = 8.5 V	-	-	100	nA
Gate Threshold Voltage	Vth	Vps = 3.5 V, Ip = 1 mA	1.0	1.35	2.0	V
Transconductance	Gm	V _{DS} = 3.5 V, I _D = 0.8 to 1.0 A	_	2.5	-	S
Drain to Source Breakdown Voltage	BVDSS	$I_{DSS} = 10 \ \mu A$	15	20	-	V
Thermal Resistance	Rth	Channel to Case	-	-	5	°C/W
Linear Gain	G∟	f = 915 MHz, P _{in} = 10 dBm, V _{DS} = 3.2 V, V _{GS} = 2.5 V, Note	-	16.0	-	dB
Output Power	Pout	f = 915 MHz, Pin = 25 dBm,	-	35.5	_	dBm
Drain Efficiency	$\eta_{ m d}$	V _{DS} = 3.2 V, V _{GS} = 2.5 V, Note	-	68	_	%
Power Added Efficiency	$\eta_{ ext{add}}$		-	65	_	%
Linear Gain	G∟	f = 1 785 MHz, P _{in} = 10 dBm, V _{DS} = 3.2 V, V _{GS} = 2.5 V, Note	_	8.5	-	dB
Output Power	Pout	f = 1 785 MHz, Pin = 25 dBm,	31.0	33.0	-	dBm
Drain Efficiency	$\eta_{ m d}$	Vps = 3.2 V, Vgs = 2.5 V, Note	29	38	-	%
Power Added Efficiency	η_{add}	1	_	35	-	%

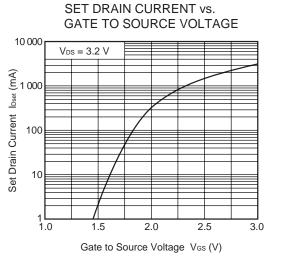
Note DC performance is 100% testing. RF performance is testing several samples per wafer. Wafer rejection criteria for standard devices is 1 reject for several samples.



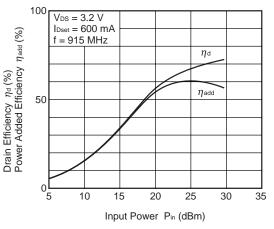


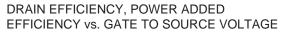


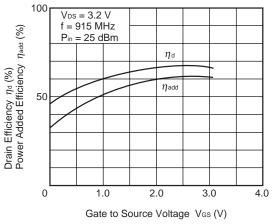




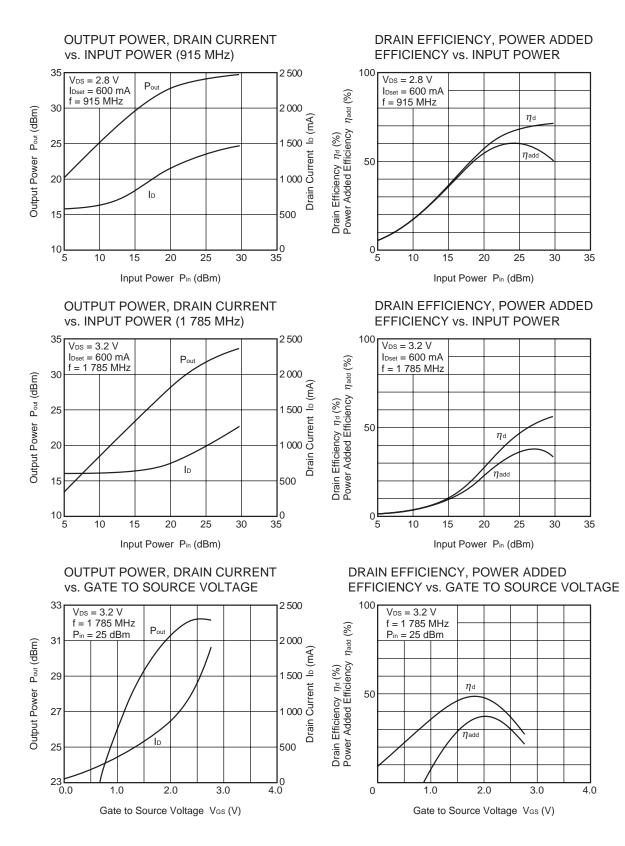
DRAIN EFFICIENCY, POWER ADDED EFFICIENCY vs. INPUT POWER

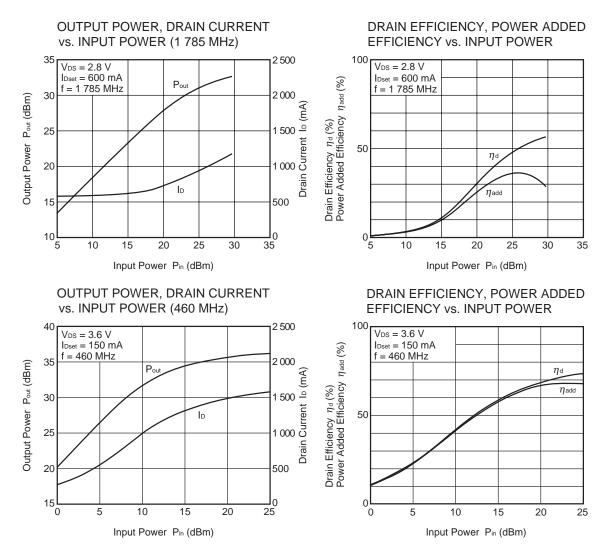






Data Sheet PU10122EJ03V0DS





Remark The graphs indicate nominal characteristics.

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S-PARAMETERS

S-parameters/Noise parameters are provided on the NEC Compound Semiconductor Devices Web site in a form (S2P) that enables direct import to a microwave circuit simulator without keyboard input.

Click here to download S-parameters.

[RF and Microwave] \rightarrow [Device Parameters]

URL http://www.csd-nec.com/

LARGE SIGNAL IMPEDANCE (VDS = 3.2 V, IDset = 600 mA, Pin = 25 dBm)

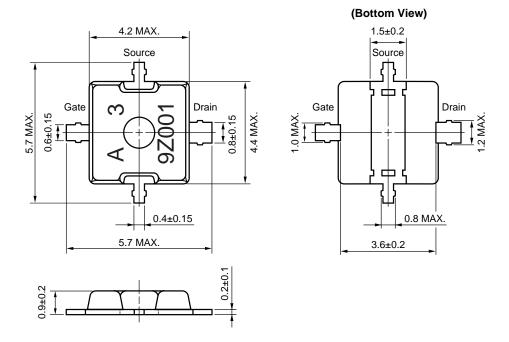
f (MHz)	$Z_{in}\left(\Omega ight)$	$Z_OL\left(\Omega ight)^{Note}$
1 785	TBD	TBD

Note ZoL is the conjugate of optimum load impedance at given voltage, idling current, input power and frequency.

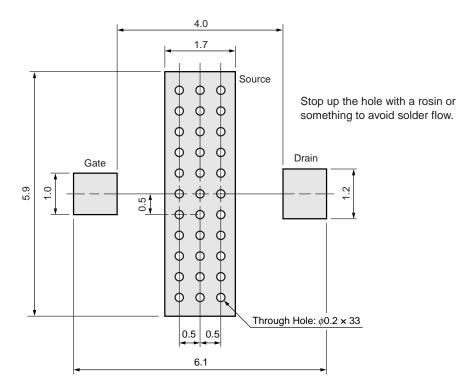
NEC

★ PACKAGE DIMENSIONS

79A (UNIT: mm)



79A PACKAGE RECOMMENDED P.C.B. LAYOUT (UNIT: mm)



RECOMMENDED SOLDERING CONDITIONS

This product should be soldered and mounted under the following recommended conditions. For soldering methods and conditions other than those recommended below, contact your nearby sales office.

Soldering Method	Soldering Conditions	Condition Symbol	
Infrared Reflow	Peak temperature (package surface temperature) Time at peak temperature Time at temperature of 220°C or higher Preheating time at 120 to 180°C Maximum number of reflow processes Maximum chlorine content of rosin flux (% mass)	: 260°C or below : 10 seconds or less : 60 seconds or less : 120±30 seconds : 3 times : 0.2%(Wt.) or below	IR260
VPS	Peak temperature (package surface temperature) Time at temperature of 200°C or higher Preheating time at 120 to 150°C Maximum number of reflow processes Maximum chlorine content of rosin flux (% mass)	: 215°C or below : 25 to 40 seconds : 30 to 60 seconds : 3 times : 0.2%(Wt.) or below	VP215
Wave Soldering	Peak temperature (molten solder temperature) Time at peak temperature Preheating temperature (package surface temperature) Maximum number of flow processes Maximum chlorine content of rosin flux (% mass)	: 260°C or below : 10 seconds or less : 120°C or below : 1 time : 0.2%(Wt.) or below	WS260
Partial Heating	Peak temperature (pin temperature) Soldering time (per pin of device) Maximum chlorine content of rosin flux (% mass)	: 350°C or below : 3 seconds or less : 0.2%(Wt.) or below	HS350-P3

Caution Do not use different soldering methods together (except for partial heating).

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